


<b>Search Notes</b>  	<b>Application/Control No.</b>  10598668	<b>Applicant(s)/Patent Under Reexamination</b>  TSUCHIYA ET AL.
	<b>Examiner</b>  Louis K Huynh	<b>Art Unit</b>  3721

SEARCHED			
Class	Subclass	Date	Examiner
53	220, 223, 224, 228, 230, 231, 232	10/10/2008	LH

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--